

ICTMS 2022: Improved wavefront reconstruction for mask based phase-contrast tomography

Emile Barjou, Benjamin Barbrel, Francesca Mastropietro, Martin Piponnier, Benoît Recur, Aboubakr Bakkali, Pascal Desbarats

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Optics & Lasers Technology Center

ICTMS 2022 : IMPROVED WAVEFRONT RECONSTRUCTION FOR MASK BASED PHASE-



Baon T, Raser BT, Matoer RA Piponier M.⁴, Recur B.³, Bakkali A.², Desbarate R. Bordeaux, CNRS, Bordeaux INP, LaBRI, UMR 5800, F-33400 Talence, France ²ALPhANOV, Rue François Mitterrand, 33400, Talence, France ³INSERM LAMC U1029, Allée Geoffroy Saint Hilaire, 33615 Pessac Cedex, France ⁴Imagine Optics, Rue François Mitterrand, 33400, Talence, France

(a)

INTRODUCTION

Phase-contrast imaging (PCI) is a promising technique that became practical in laboratory setups thanks to high-power microfocus X-Ray sources [1]. Coupled with high-resolution (HR) detectors, HR-PCI can be achieved in a single exposure using Hartmann masks, which captures the sample-induced deformation of the x-ray wavefront (WF) through the local deflections of X-rays. The reconstructed wavefront then provides information on the complex index of refraction of the sample [2,3]. With accurate measurement of the projected phase shifts, a phase tomogram can be reconstructed to obtain localized information on the sample material.



PECONSTRUCTION

VVAVEFRUN

Algorithms dedicated to reconstruct wavefront (WF) acquired using Hartmann sensors have been largely described in literature. The most common is described in [4] as an iterative reconstruction algorithm (IR-WF).



Fig. 3: Examples of direct WF reconstruction of a juvenile oyster shell at different angles.

By processing each projection individually, artifacts appear due to the noise in the deflection maps. Those incoherent artifacts alter the tomographic reconstruction.

TOMOGRAPHY + IR-WF



Hartmann Rotation axis Detector mask

Fig. 1 : Diagram of our acquisition setup.

HARTMANN SENSOR

A Hartmann sensor consists of a mask drilled with a micrometric holes placed in front of a detector, that defines an array of beamlets.

The phase-related information is contained in the deflection of the individual beamlets. Different Hartmann configurations were tested in our setup to improve deflection sensitivity, spatial resolution and SNR.



To improve the homogeneity between the projections during IR-WF, we developed a 3D-driven algorithm that converges on the volume rather than the projections. An IR-WF iteration is applied to the current volume projection, and then compared to the raw projection to compute the error to back-propagate.



Fig. 4 : Diagram of the simultaneous WF and CT reconstructions. Both reconstructions converge simultaneously, ensuring that any single wavefront has to be coherent with all others.

Fig. 2 : Examples of horizontal deflections extracted from the raw image acquired with this setup on two samples. (a) Shell of a juvenile oyster from Institut Fresnel, Marseille. (b) Tube filled with glass silicate microspheres.

				Sequential	Simultaneou s
			PSNR local	11,016	12,107
	Car	Car	PSNR full	11,685	15,519
			SNR local	0,634	1,279
			SNR full	0,863	0,924
	C 1	O' 1	CNR local	11,016	27,062
-Sequential -Simultaneous	Sequential	Simultaneous	CNR full	10.088	14.333
				Sequential	Simultaneou s
			PSNR local	Sequential 6,265	Simultaneou s 9,643
			PSNR local PSNR full	Sequential 6,265 9,242	Simultaneou S 9,643 9,406
			PSNR local PSNR full SNR local	Sequential 6,265 9,242 1,055	Simultaneou s 9,643 9,406 2,315
			PSNR local PSNR full SNR local SNR full	Sequential 6,265 9,242 1,055 1,075	Simultaneou S 9,643 9,406 2,315 1,259
			PSNR local PSNR full SNR local SNR full CNR local	Sequential 6,265 9,242 1,055 1,075 6,100	Simultaneou S 9,643 9,406 2,318 1,258 19,128

Tab. 1 : Metrics measured from the example layers. Local metrics are obtained by manually selecting the signal and noise regions of interest, while the full metrics are obtained on complete image the without segmentation.

Formula used : SNR = Mean/StdDevPSNR = Max/StdDevCNR = (Max-Min)/StdDev

Plot. 1 : Gray level along the lines of the example layers, for both sequential and simultaneous reconstructions.

COMPADICON

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ERDF.

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This method allows to retrieve a more homogeneous result with both better contrast-to-noise and signal-to-noise ratios than the consecutive application of IR-WF and IR-CT in both sample datasets.

Since only the order of the operations differs, the computation time for the two methods is similar.



ALPhANOV - Optics and Lasers Technology Center Institut d'Optique d'Aquitaine - Rue François Mitterrand 33400 - France - Ph.: +33 (0)5 54 24 52 00 info@alphanov.com - www.alphanov.com